

FSB50450S

Smart Power Module (SPM[®])

Features

- 500V 3.0A 3-phase FRFET inverter including high voltage integrated circuit (HVIC)
- 3 divided negative dc-link terminals for inverter current sens ing applications
- HVIC for gate driving and undervoltage protection
- 3/5V CMOS/TTL compatible, active-high interface
- Optimized for low electromagnetic interference
- Isolation voltage rating of 1500Vrms for 1min.
- Surface mounted device package
- Moisture Sensitive Level (MSL) 3

General Description

FSB50450S is a tiny smart power module (SPM[®]) based on FRFET technology as a compact inverter solution for small power motor drive applications such as fan motors and water suppliers. It is composed of 6 fast-recovery MOSFET (FRFET), and 3 half-bridge HVICs for FRFET gate driving. FSB50450S provides low electromagnetic interference (EMI) characteristics with optimized switching speed. Moreover, since it employs FRFET as a power switch, it has much better ruggedness and larger safe operation area (SOA) than that of an IGBT-based power module or one-chip solution. The package is optimized for the thermal performance and compactness for the use in the built-in motor application and any other application where the assembly space is concerned. FSB50450S is the most solution for the compact inverter providing the energy efficiency, compactness, and low electromagnetic interference.



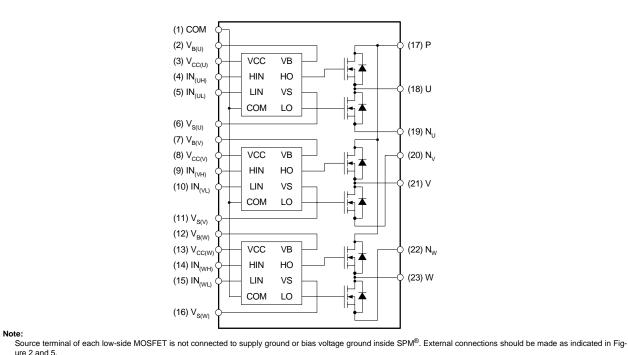
Absolute Maximum Ratings

| Symbol | Parameter | Conditions | Rating | Units | |
|--|--|--|----------------|------------------|--|
| V _{PN} | DC Link Input Voltage, Drain-source Voltage of each FRFET | | 500 | V | |
| I _{D25} | Each FRFET Drain Current, Continuous | $T_{\rm C} = 25^{\circ}{\rm C}$ | 1.5 | А | |
| I _{D80} | Each FRFET Drain Current, Continuous | $T_{\rm C} = 80^{\circ}{\rm C}$ | 1.0 | А | |
| I _{DP} | Each FRFET Drain Current, Peak | T _C = 25℃, PW < 100 μs | 3.0 | А | |
| PD | Maximum Power Dissipation | T _C = 25℃, Each FRFET | 10 | W | |
| V _{CC} Control Supply Voltage | | Applied between V _{CC} and COM | 20 | V | |
| V _{BS} High-side Bias Voltage | | Applied between V _{B(U)} -U, V _{B(V)} -V, V _{B(W)} -W | 20 | V | |
| V _{IN} Input Signal Voltage | | Applied between IN and COM | -0.3 ~ VCC+0.3 | V | |
| T _J Operating Junction Temperature | | | -20 ~ 150 | ĉ | |
| T _{STG} | Storage Temperature | | -50 ~ 150 | C | |
| R _{0JC} Junction to Case Thermal Resistance | | Each FRFET under inverter operating con- dition (Note 1) | 8.9 | £\M | |
| V _{ISO} Isolation Voltage | | 60Hz, Sinusoidal, 1 minute, Connection pins to heatsink | 1500 | V _{rms} | |

| FSB50450S |
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| Smart Powe |
| r Module (|
| (SPM®) |

Pin Descriptions

| Pin Number | Pin Name | Pin Description |
|------------|--------------------|---|
| 1 | СОМ | IC Common Supply Ground |
| 2 | V _{B(U)} | Bias Voltage for U Phase High Side FRFET Driving |
| 3 | V _{CC(U)} | Bias Voltage for U Phase IC and Low Side FRFET Driving |
| 4 | IN _(UH) | Signal Input for U Phase High-side |
| 5 | IN _(UL) | Signal Input for U Phase Low-side |
| 6 | V _{S(U)} | Bias Voltage Ground for U Phase High Side FRFET Driving |
| 7 | V _{B(V)} | Bias Voltage for V Phase High Side FRFET Driving |
| 8 | V _{CC(V)} | Bias Voltage for V Phase IC and Low Side FRFET Driving |
| 9 | IN _(VH) | Signal Input for V Phase High-side |
| 10 | IN _(VL) | Signal Input for V Phase Low-side |
| 11 | V _{S(V)} | Bias Voltage Ground for V Phase High Side FRFET Driving |
| 12 | V _{B(W)} | Bias Voltage for W Phase High Side FRFET Driving |
| 13 | V _{CC(W)} | Bias Voltage for W Phase IC and Low Side FRFET Driving |
| 14 | IN _(WH) | Signal Input for W Phase High-side |
| 15 | IN _(WL) | Signal Input for W Phase Low-side |
| 16 | V _{S(W)} | Bias Voltage Ground for W Phase High Side FRFET Driving |
| 17 | Р | Positive DC-Link Input |
| 18 | U | Output for U Phase |
| 19 | NU | Negative DC-Link Input for U Phase |
| 20 | N _V | Negative DC–Link Input for V Phase |
| 21 | V | Output for V Phase |
| 22 | N _W | Negative DC-Link Input for W Phase |
| 23 | W | Output for W Phase |



ure 2 and 5.

Figure 1. Pin Configuration and Internal Block Diagram (Bottom View)

Electrical Characteristics (T_J = 25°C, V_{CC}=V_{BS}=15V Unless Otherwise Specified)

Inverter Part (Each FRFET Unless Otherwise Specified)

| Symbol | Parameter | Conditions | | Тур | Max | Units |
|--------------------------------|--|--|---|--------|-----|-------|
| BV _{DSS} | Drain-Source Breakdown Voltage | V _{IN} = 0V, I _D = 250μA (Note 2) | | - | - | V |
| $\Delta BV_{DSS}/\Delta T_{J}$ | Breakdown Voltage Tem- perature Coefficient | $I_D = 250\mu A$, Referenced to $25^{\circ}C$ | | 0.53 | - | V |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{IN} = 0V, V _{DS} = 500V | - | - | 250 | μΑ |
| R _{DS(on)} | Static Drain-Source On-Resistance | V _{CC} = V _{BS} = 15V, V _{IN} = 5V, I _D = 1.0A | | 1.9 | 2.4 | Ω |
| V _{SD} | Drain-Source Diode Forward Voltage | $V_{CC} = V_{BS} = 15V, V_{IN} = 0V, I_D = -1.0A$ | | - | 1.2 | V |
| t _{ON} | | $\label{eq:VPN} \begin{array}{l} V_{PN} = 300V, \ V_{CC} = V_{BS} = 15V, \ I_D = 1.0A \\ V_{IN} = 0V \leftrightarrow 5V \\ \mbox{Inductive load L=3mH} \\ \mbox{High- and low-side FRFET switching} \end{array}$ | - | 1152 | - | ns |
| t _{OFF} | | | - | 600 | - | ns |
| t _{rr} | Switching Times | | - | 185 | - | ns |
| E _{ON} | | | - | 85 | - | μJ |
| E _{OFF} | OFF (Note 3) | | - | 11 | - | μJ |
| RBSOA | Reverse-bias Safe Oper- ating Area | ' 11 = 150% EUII 50 | | Square | | |

Control Part (Each HVIC Unless Otherwise Specified)

| Symbol | Parameter | Conditions | | Min | Тур | Max | Units |
|-------------------|-----------------------------------|---|---|-----|-----|-----|-------|
| IQCC | Quiescent V _{CC} Current | V _{CC} =15V, V _{IN} =0V | Applied between $V_{\mbox{\scriptsize CC}}$ and COM | - | - | 160 | μA |
| I _{QBS} | Quiescent V _{BS} Current | V _{BS} =15V, V _{IN} =0V | Applied between $V_{B(U)}$ -U, $V_{B(V)}$ -V, $V_{B(W)}$ -W | - | - | 100 | μA |
| UV _{CCD} | Low-side Undervoltage | V _{CC} Undervoltage Protection Detection Level | | 7.4 | 8.0 | 9.4 | V |
| UV _{CCR} | Protection (Figure 6) | V _{CC} Undervoltage Protection Reset Level | | 8.0 | 8.9 | 9.8 | V |
| UV _{BSD} | High-side Undervoltage | V _{BS} Undervoltage Protection Detection Level | | 7.4 | 8.0 | 9.4 | V |
| UV _{BSR} | Protection (Figure 7) | V _{BS} Undervoltage Protection Reset Level | | 8.0 | 8.9 | 9.8 | V |
| V _{IH} | ON Threshold Voltage | Logic High Level | | | - | - | V |
| V _{IL} | OFF Threshold Voltage | Logic Low Level | Applied between IN and COM | - | - | 0.8 | V |
| I _{IH} | Input Pige Current | $V_{IN} = 5V$ | Applied between IN and COM | - | 10 | 20 | μA |
| ۱ _{IL} | Input Bias Current | $V_{IN} = 0V$ | Applied between in and COM | - | - | 2 | μΑ |

Note:

1. For the measurement point of case temperature T_C , please refer to Figure 3 in page 4.

2. BV_{DSS} is the absolute maximum voltage rating between drain and source terminal of each FRFET inside SPM[®]. V_{PN} should be sufficiently less than this value considering the effect of the stray inductance so that V_{DS} should not exceed BV_{DSS} in any case.

 t_{ON} and t_{OFF} include the propagation delay time of the internal drive IC. Listed values are measured at the laboratory test condition, and they can be different according to the field applications due to the effect of different printed circuit boards and wirings. Please see Figure 4 for the switching time definition with the switching test circuit of Figure 5.

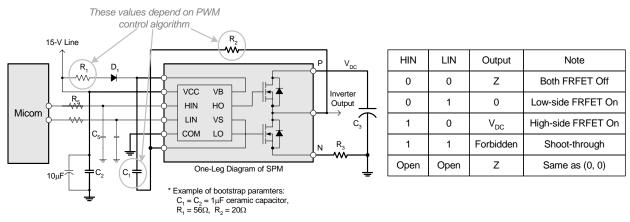
4. The peak current and voltage of each FRFET during the switching operation should be included in the safe operating area (SOA). Please see Figure 5 for the RBSOA test circuit that is same as the switching test circuit.

Package Marking & Ordering Information

| Device Marking | Device | Package | Reel Size | Packing Type | Quantity |
|----------------|-----------|---------|-----------|--------------|----------|
| FSB50450S | FSB50450S | SPM23BA | 330mm | Tape & reel | 450 |

Recommended Operating Conditions

| Symbol | Parameter | Conditions | Value | | | Units |
|----------------------|---|--|-------|------|-----------------|-------|
| Symbol | Farameter | Conditions | Min. | Тур. | Max. | Units |
| V _{PN} | Supply Voltage | Applied between P and N | - | 300 | 400 | V |
| V _{CC} | Control Supply Voltage | Applied between $V_{\mbox{\scriptsize CC}}$ and COM | 13.5 | 15 | 16.5 | V |
| V _{BS} | High-side Bias Voltage | Applied between V_B and output(U, V, W) | 13.5 | 15 | 16.5 | V |
| V _{IN(ON)} | Input ON Threshold Voltage | Applied between IN and COM | 3.0 | - | V _{CC} | V |
| V _{IN(OFF)} | Input OFF Threshold Voltage | | 0 | - | 0.6 | V |
| t _{dead} | Blanking Time for Preventing Arm-short | V_{CC} =V _{BS} =13.5 ~ 16.5V, T _J \leq 150°C | 1.0 | - | - | μs |
| f _{PWM} | PWM Switching Frequency | $T_J \leq 150^{\circ}C$ | - | 15 | - | kHz |
| т _с | Case Temperature | $T_{J} \leq 150^{\circ}C$ | -20 | - | 125 | ĉ |



Note:

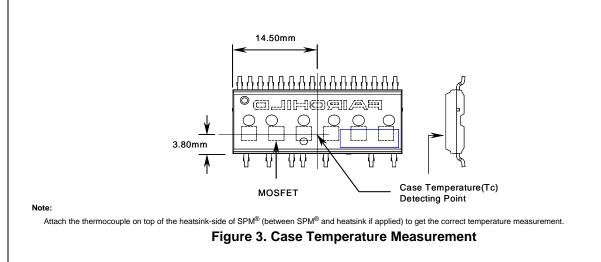
(1) It is recommended the bootstrap diode D_1 to have soft and fast recovery characteristics with 600-V rating

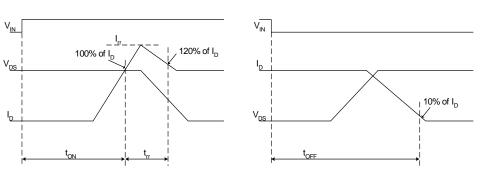
(2) Parameters for bootsrap circuit elements are dependent on PWM algorithm. For 15 kHz of switching frequency, typical example of parameters is shown above.

(3) RC coupling(R₅ and C₅) at each input (indicated as dotted lines) may be used to prevent improper input signal due to surge noise. Signal input of SPM[®] is compatible with standard CMOS or LSTTL outptus.

(4) Bold lines should be short and thick in PCB pattern to have small stray inductance of circuit, which results in the reduction of surge voltage. Bypass capacitors such as C₁, C₂ and C₃ should have good high-frequency characteristics to absorb high-frequency ripple current.

Figure 2. Recommended CPU Interface and Bootstrap Circuit with Parameters





(a) Turn-on (b) Turn-off Figure 4. Switching Time Definition

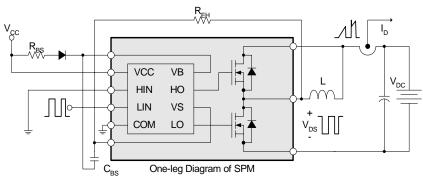
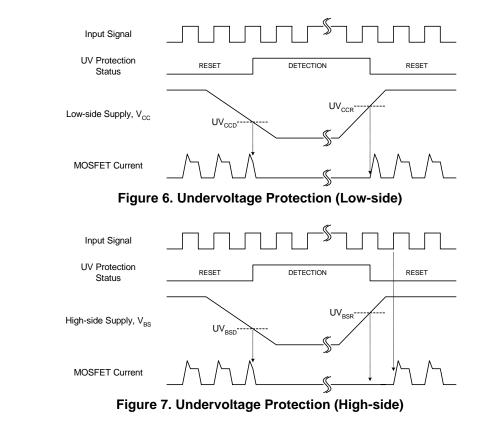


Figure 5. Switching and RBSOA(Single-pulse) Test Circuit (Low-side)



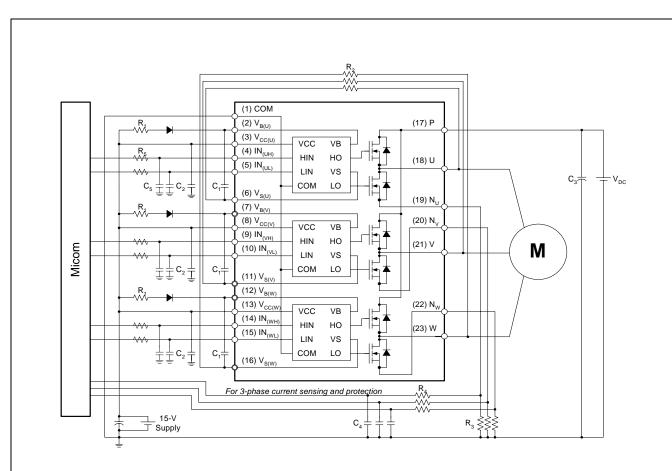
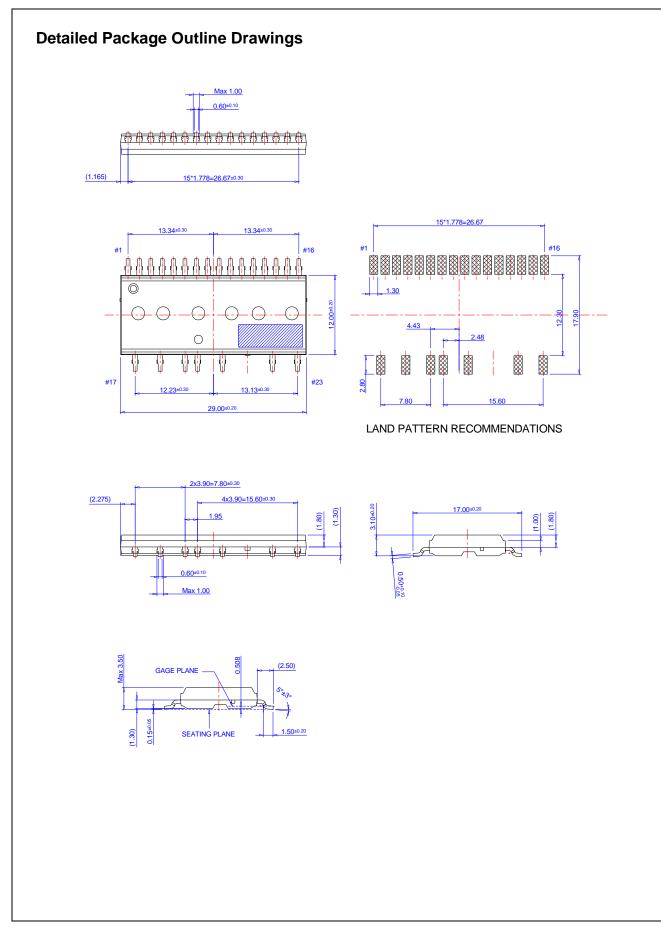


Figure 8. Example of Application Circuit



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